

FDS6676AS

30V N-Channel PowerTrench® SyncFET[™]

General Description

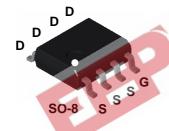
The FDS6676AS is designed to replace a single SO-8 MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{\text{DS(ON)}}$ and low gate charge. The FDS6676AS includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

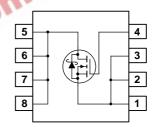
Applications

- DC/DC converter
- Low side notebook

Features

- 14.5 A, 30 V. $R_{DS(ON)}$ max= 6.0 m Ω @ V_{GS} = 10 V $R_{DS(ON)}$ max= 7.25 m Ω @ V_{GS} = 4.5 V
- Includes SyncFET Schottky body diode
- Low gate charge (45nC typical)
- High performance trench technology for extremely low R_{DS(ON)} and fast switching
- High power and current handling capability





Absolute Maximum Ratings T

T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	14.5	A
	– Pulsed		50	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
T _J , T _{STG}	Operating and Storage Junction Temperat	ure Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (N	lote 1a)	50	°C/W
R _{e,IC}	Thermal Resistance, Junction-to-Case (I	Note 1)	25	

Package Marking and Ordering Information

	3			
Device Marking	Device	Reel Size	Tape width	Quantity
FDS6676AS	FDS6676AS	13"	12mm	2500 units
FDS6676AS	FDS6676AS_NL (Note 3)	13"	12mm	2500 units

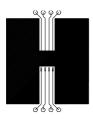
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	1		I	l	I
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 1 \text{ mA}$	30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		28		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			500	μΑ
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	1	1.5	3	V
$\Delta V_{GS(th)}$ ΔT_J	Gate Threshold Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		-3.3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 14.5 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \qquad I_D = 13.2 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 14.5 \text{ A}, T_J = 125^{\circ}\text{C}$		4.5 5.9 6.7	6.0 7.25 8.5	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	50			Α
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 14.5 \text{ A}$	70	66		S
Dynamic	: Characteristics	7. 34	-10			
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$	0	2510		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		710		pF
C _{rss}	Reverse Transfer Capacitance	CO.		270		pF
R_G	Gate Resistance	$V_{GS} = 15 \text{ mV}, \qquad f = 1.0 \text{ MHz}$		1.6	2.8	Ω
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		10	20	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		12	22	ns
t _{d(off)}	Turn-Off Delay Time			43	69	ns
t _f	Turn-Off Fall Time			29	46	ns
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$		17	31	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		22	35	ns
$t_{d(off)}$	Turn-Off Delay Time			34	54	ns
t _f	Turn-Off Fall Time			29	46	ns
Q _{g(TOT)}	Total Gate Charge at Vgs=10V			45	63	nC
Q_g	Total Gate Charge at Vgs=5V	$V_{DD} = 15 \text{ V}, I_D = 14.5 \text{ A},$		25	35	nC
Q_{gs}	Gate-Source Charge			7		nC
Q_{gd}	Gate-Drain Charge			8		nC

Electrical Characteristics

 $T_{A} = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain–Source Diode Characteristics and Maximum Ratings						
V _{SD}	Drain-Source Diode Forward Voltage		te 2)	0.4 0.5	0.7	V
t _{rr}	Diode Reverse Recovery Time	$I_F = 14.5A,$		27		nS
I _{RM}	Diode Reverse Recovery Current	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$ (No	te 3)	1.9		Α
Q _{rr}	Diode Reverse Recovery Charge			26		nC

1. R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 50°/W when mounted on a 1 in² pad of 2 oz copper



b) 105°/W when mounted on a .04 in² pad of 2 oz copper



c) 125°/W when mounted on a

See "SyncFET Schottky body diode characteristics" below



- **Δ.** Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0% **3.** FDS6676AS_NL is a lead free product. The FDS6676AS_NL marking will appear on the reel label.

Typical Characteristics

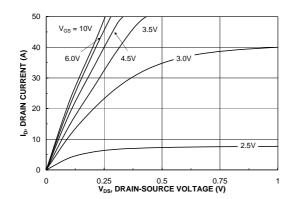


Figure 1. On-Region Characteristics.

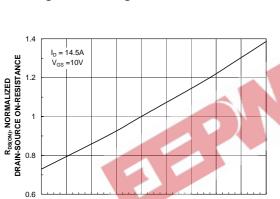


Figure 3. On-Resistance Variation with Temperature.

-15 5 25 45 65 85 T_J, JUNCTION TEMPERATURE (°C)

125

-35

-55

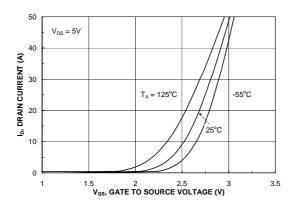


Figure 5. Transfer Characteristics.

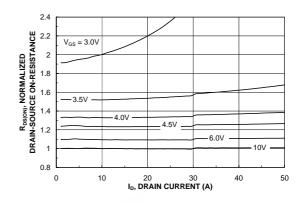


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

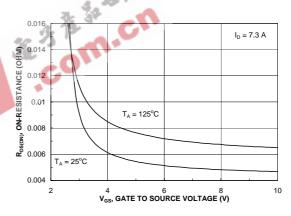


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

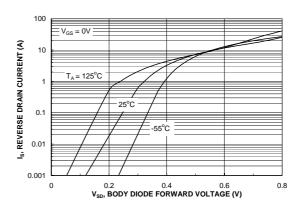


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

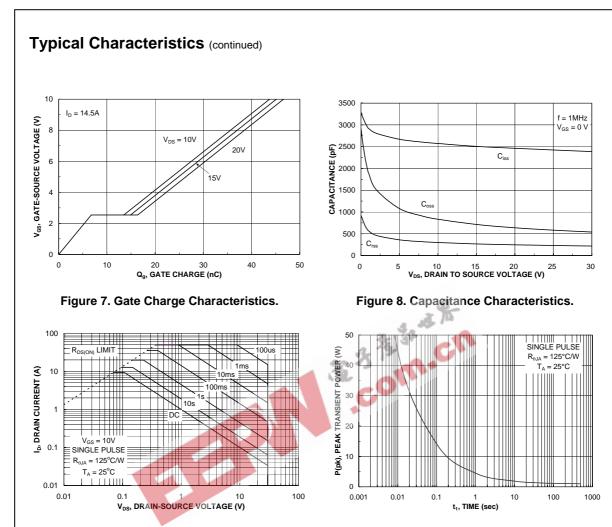


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

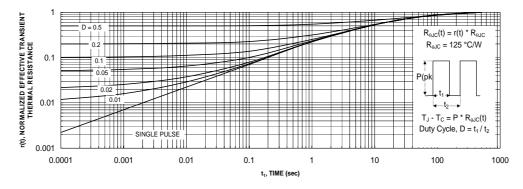


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS6676AS.

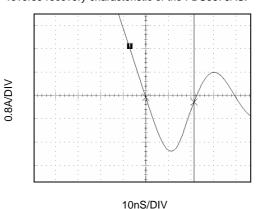


Figure 12. FDS6676AS SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6676).

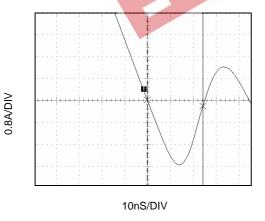


Figure 13. Non-SyncFET (FDS6676) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

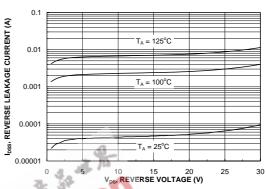
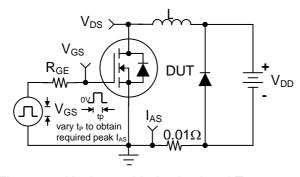


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

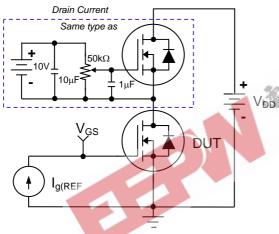
Typical Characteristics



BV_{DSS} V_{DS} V_{DD}

Figure 15. Unclamped Inductive Load Test Circuit

Figure 16. Unclamped Inductive Waveforms



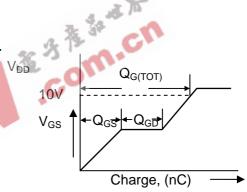
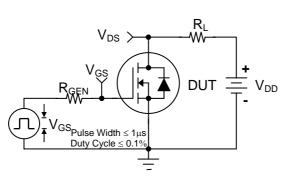


Figure 17. Gate Charge Test Circuit

Figure 18. Gate Charge Waveform



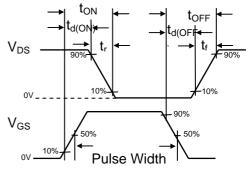


Figure 19. Switching Time Test Circuit

Figure 20. Switching Time Waveforms

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Rev. I13